

Notice of References CitedApplication/Control No.
09/360,069Applicant(s)/Patent Under
Reexamination
WOHL ET AL.Examiner
Eduardo Garcia-OteroArt Unit
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,696,771	12-1997	Beausang et al.	714/726
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	U	CRC Handbook of Mathematical Sciences, 5th Edition, William H. Beyer, CRC Press, Inc., Fourth Printing, 1985, ISBN 0-8493-0655-8, page 47.
	V	Tutorial and Survey Paper: Gate-Level Test Generation for Sequential Circuits by Kwang-Ting Cheng, ACM Transactions on Design Automation of Electronic Systems, Vol. 1, No. 4, October 1996, Pages 405-442.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.